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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: B. Beaman et al.

Date: August 2, 2000

Serial Number: 09/088,394

Group Art Unit: 2858

Filed: June 1, 1998

Examiner: V. Nguyen

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, Docket No.: YO993-028AB

TEST PROBE AND METHODS OF USE THEREOF

FRY COPY RECEIVED

Assistant Commissioner for Patents

AUG 0 2 2000

Washington, D.C. 20231

TECHNOLOGY CERTER 2800

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this Amendment (11 pages) being facsimile transmitted under Rule 37 CFR 161(d) to the U.S. Patent and Trademark Office

to (703) 305-3431 on August 2/2000

Daniel P. Morris Reg. No. 32,053

Sir:

AMENDMENT

In response to the Office Action dated April 19, 2000,

IN THE CLAIMS

| §. (Amended) An electronic device probe for probing an electronic device comprising:

a first space transformer having a first surface;

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said first surface having a first plurality of contact locations;

S.N. 09/088,394

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